

Notice of Allowability	Application No.	Applicant(s)	ARORA ET AL. Art Unit 2825
	10/806,680		
	Examiner		
	Sun J. Lin		

— The MAILING DATE of this communication appears on the cover sheet with the correspondence address—

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. This communication is responsive to Amendments & Remarks filed on 03/01/2006.

2. The allowed claim(s) is/are 1 and 3-32, renumbered (37 CFR 1.126).

3. Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).

a) All b) Some* c) None of the:

1. Certified copies of the priority documents have been received.

2. Certified copies of the priority documents have been received in Application No. _____.

3. Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

* Certified copies not received: _____.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.
THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.

4. A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.

5. CORRECTED DRAWINGS (as "replacement sheets") must be submitted.

(a) including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
1) hereto or 2) to Paper No./Mail Date _____.

(b) including changes required by the attached Examiner's Amendment / Comment or in the Office action of
Paper No./Mail Date _____.

Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).

6. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

Attachment(s)

- 1. Notice of References Cited (PTO-892)
- 2. Notice of Draftsperson's Patent Drawing Review (PTO-948)
- 3. Information Disclosure Statements (PTO-1449 or PTO/SB/08),
Paper No./Mail Date _____
- 4. Examiner's Comment Regarding Requirement for Deposit
of Biological Material
- 5. Notice of Informal Patent Application (PTO-152)
- 6. Interview Summary (PTO-413),
Paper No./Mail Date _____.
- 7. Examiner's Amendment/Comment
- 8. Examiner's Statement of Reasons for Allowance
- 9. Other _____.

Examiner's Amendment

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

The application has been amended, based on Amendments filed on 03/01/2006, to correct several informalities as listed below:

Claim 1, line 8, delete —and—.

Claim 11, line 7, after "first" insert —conductor—.

Claim 32, line 7, after "first" insert —conductor—.

Reasons for Allowance

Claims 1 and 3 – 32 are allowed over the prior art of record. An examiner's statement of reasons for allowance is given in the following:

Claim 32 is allowed because it is a newly added independent claim, which incorporates allowable limitations of Claim 20 and all limitations of its base Claim 11.

Claims 1 and 3 – 31 are allowed because the prior art does not teach or fairly suggest the following subject matter:

- A method for determining process parameters of an integrated circuit interconnect using a test structure, which comprises a first plate a second plate, a first conductor disposed between the first plate and the second plate, and a second conductor disposed between the first plate and the second plate, the method comprising determining a first capacitance between the first plate and the first conductor or the second conductor and determining a second capacitance between the second plate and the first conductor and the second conductor, wherein the first capacitance and the second capacitance are determined separately in combination with other limitation as recited in independent **Claim 1**;
- A method for determining coupling capacitances of a test structure within an integrated circuit, the test structure comprises a first plate a second plate, a first conductor disposed between the first plate and the second

plate, and a second conductor disposed between the first plate and the second plate, the method comprising determining a first capacitance between the first plate and the first conductor or the second conductor and determining a second capacitance between the second plate and the first conductor and the second conductor, wherein the first capacitance and the second capacitance are determined separately in combination with other limitation as recited in independent **Claim 11**;

- An integrated circuit including at least one test structure, the test structure comprising a first multiplexer circuit connected to a first conductive plate, a second multiplexer circuit connected to a second conductive plate and a CBCM circuit connected to the first multiplexer circuit and the second multiplexer circuit in combination with other limitation as recited in independent **Claim 22**.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance".

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Sun J. Lin whose telephone number is (571) 272 - 1899. The examiner can normally be reached on Monday to Friday from 9:00am to 6:00pm.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-1782.

Sun J. Lin
Patent Examiner
Art Unit 2825
March 13, 2006





Reviewed

OK

gsh

3-8-06

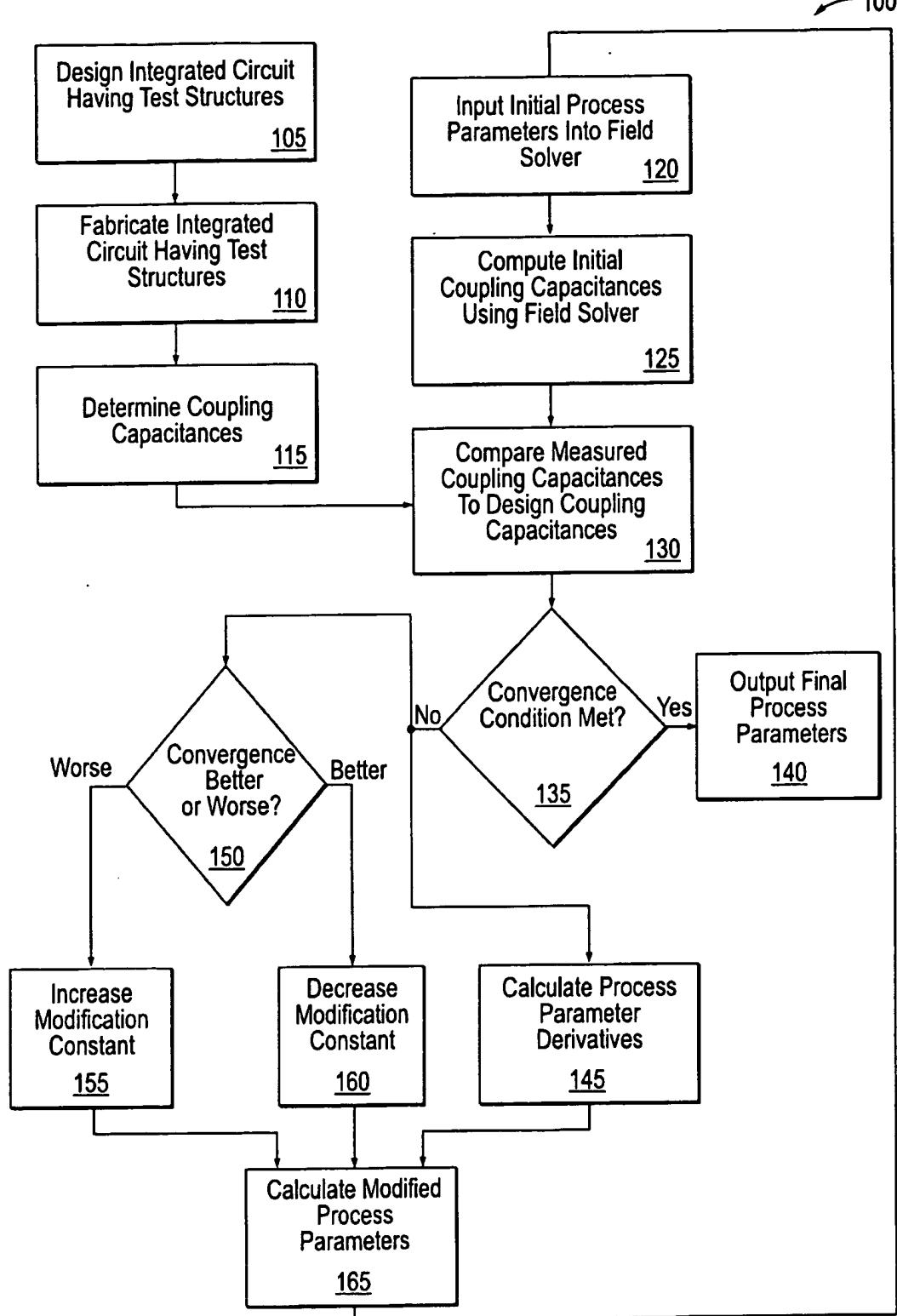


FIG. 1

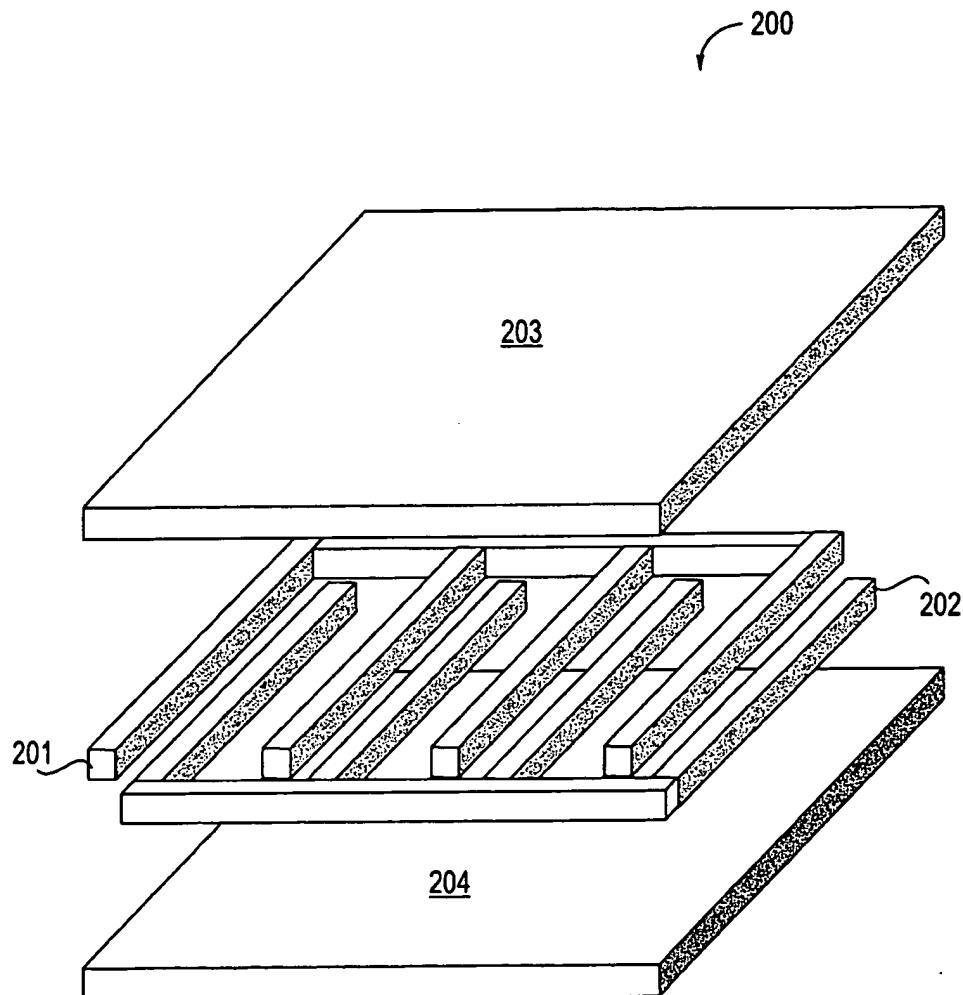


FIG. 2A

Replacement Sheet }

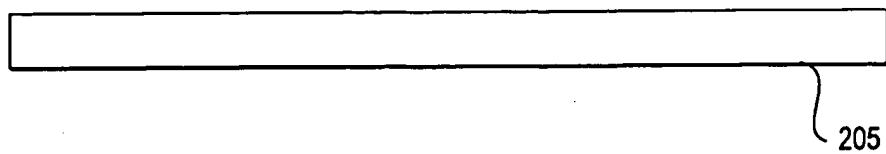
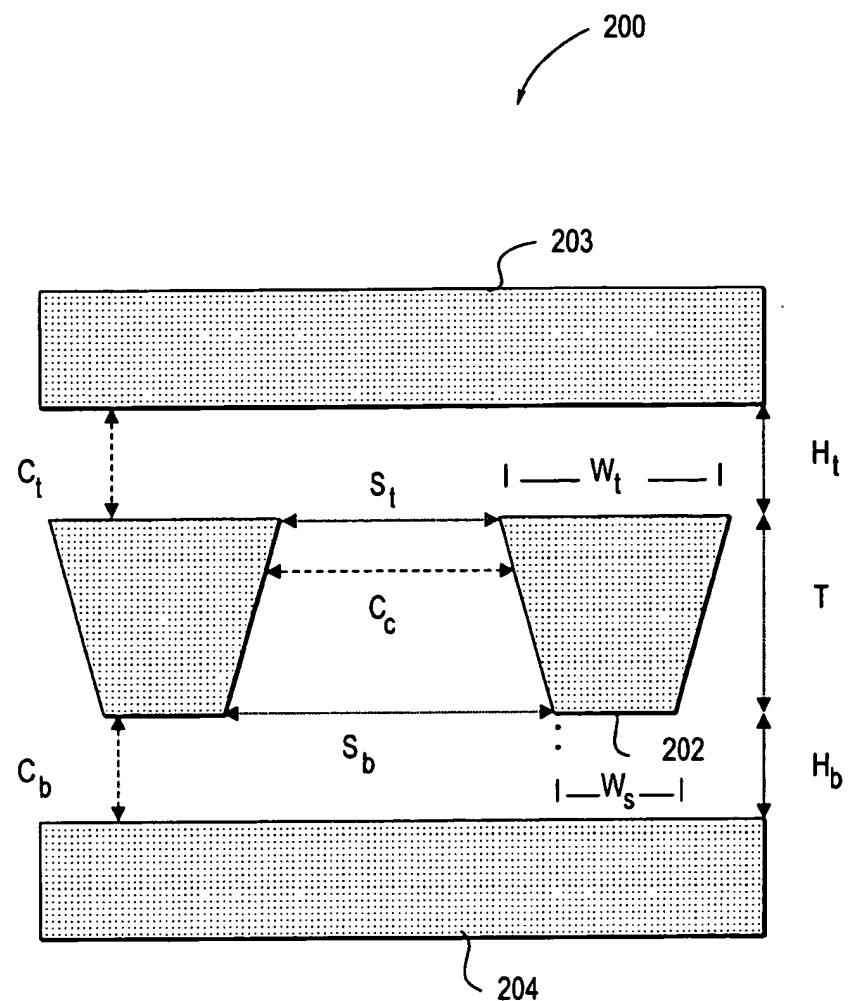


FIG. 2B

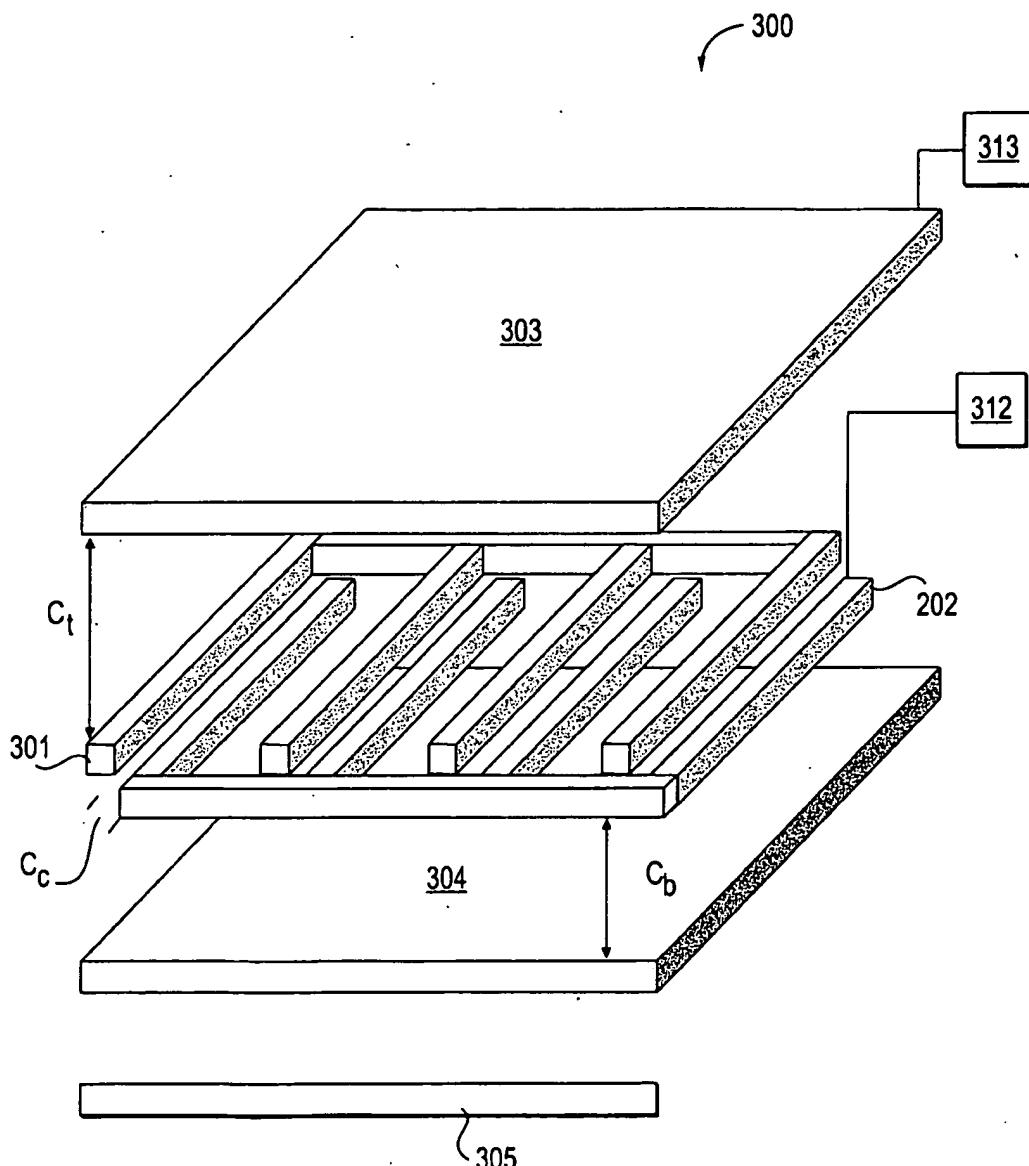


FIG. 3

